



Institute for Electronics Engineering

Prof. Dr.-Ing. Dr.-Ing. habil. Robert Weigel



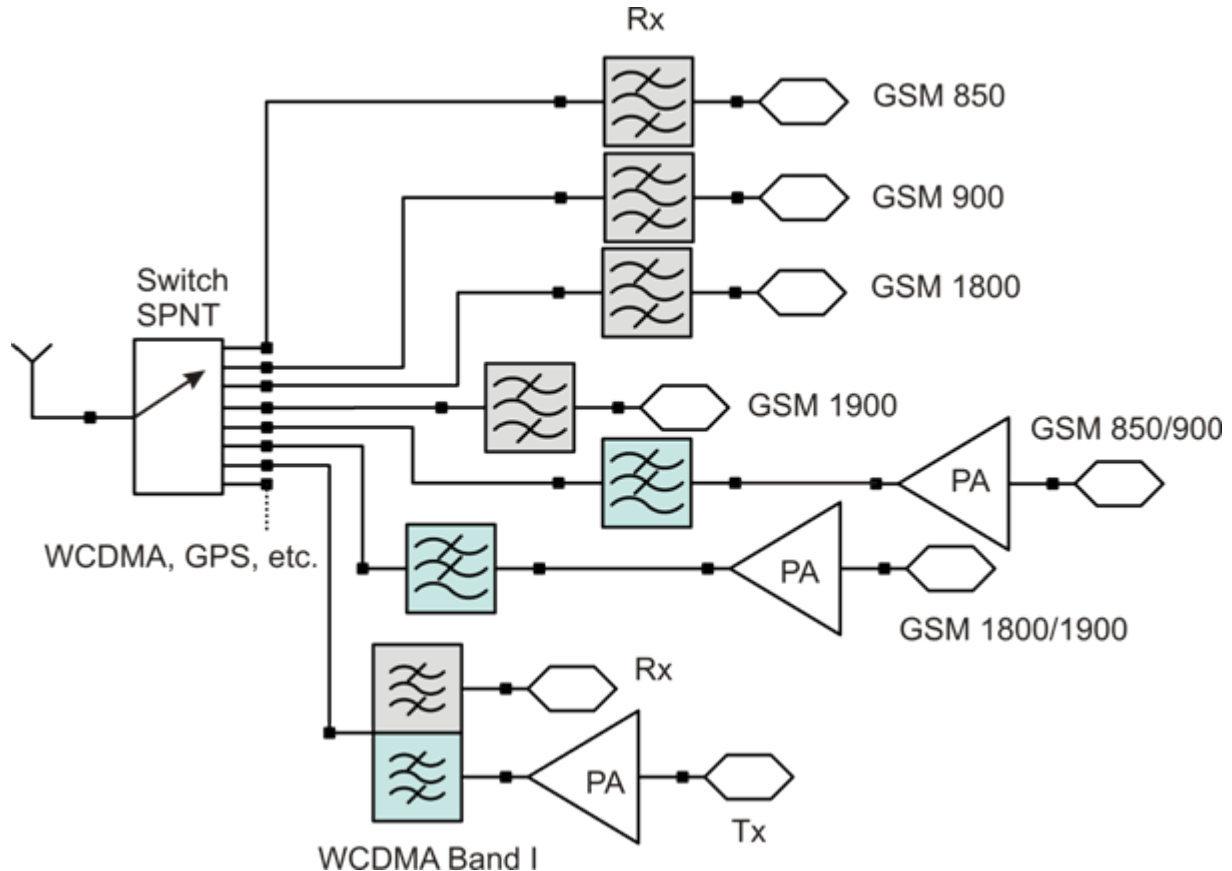
Tunable BST-Varactor-Based Matching Networks for Mobile Radio Applications

Errikos Lourandakis, Matthias Schmidt, Robert Weigel
IMS 2008 - Workshop

Outline

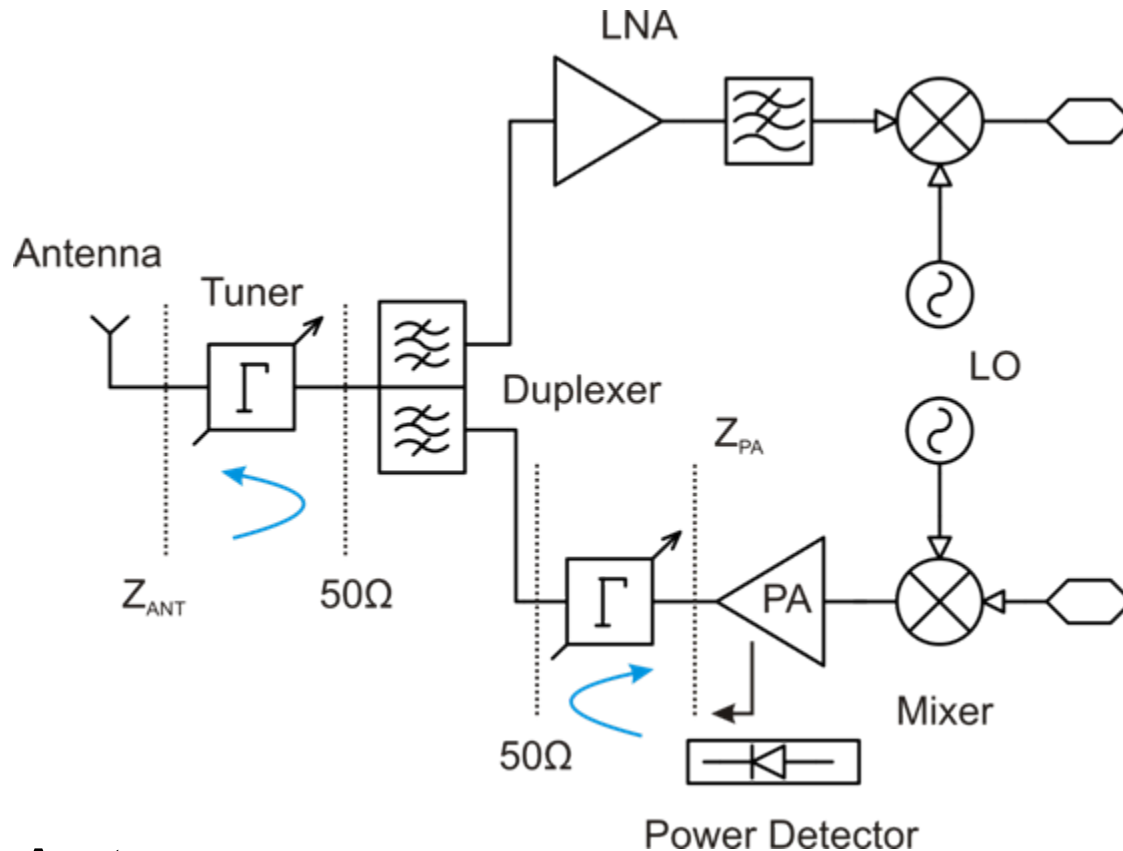
- Motivation
- BST Thin-Film Varactors
- Matching Network Topologies
 - L, Π , T, and Reflection-type
- Linear and Nonlinear Behaviour
- Measurement Results
- Summary

Motivation



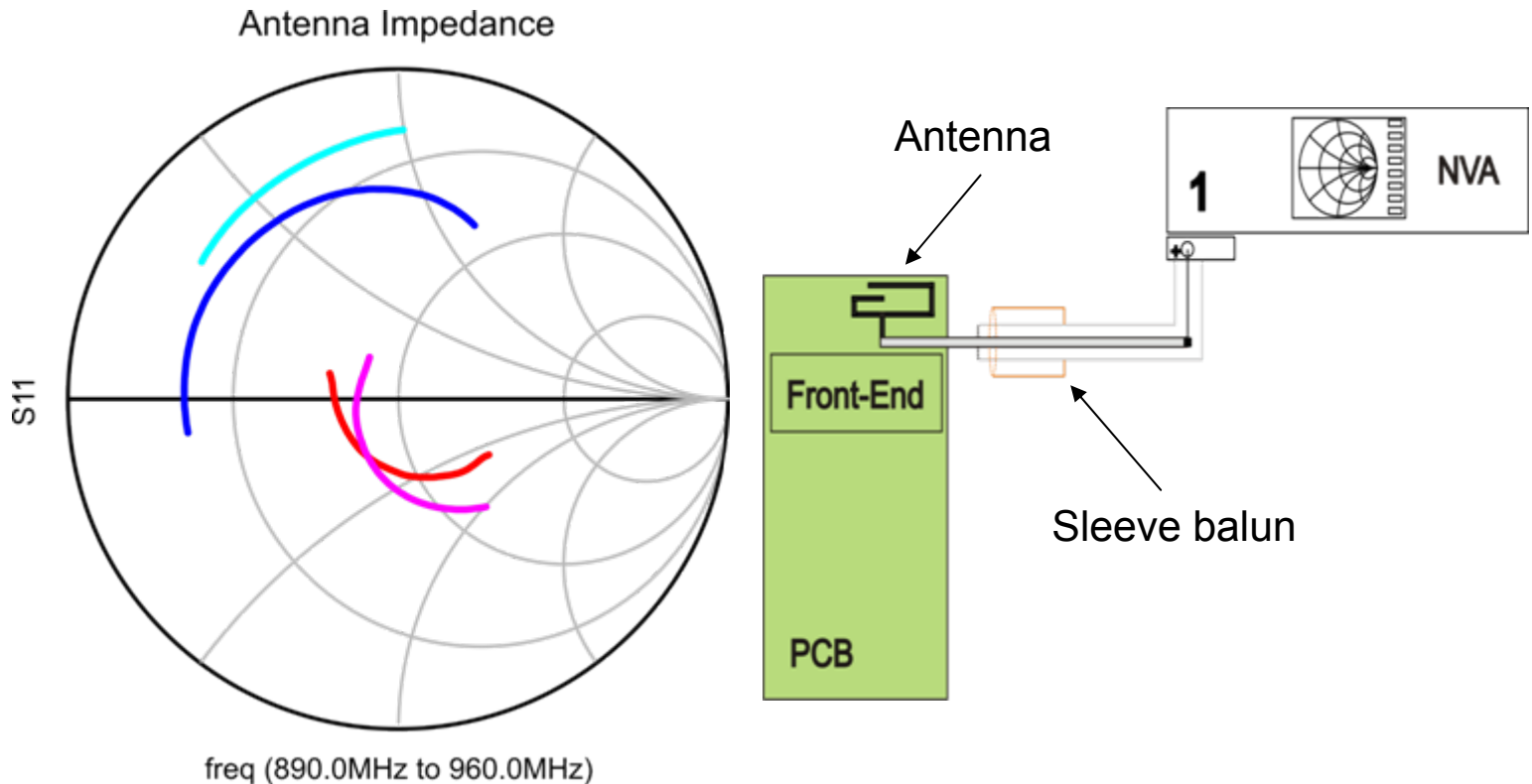
- Increasing number of mobile standards

Mismatch Conditions



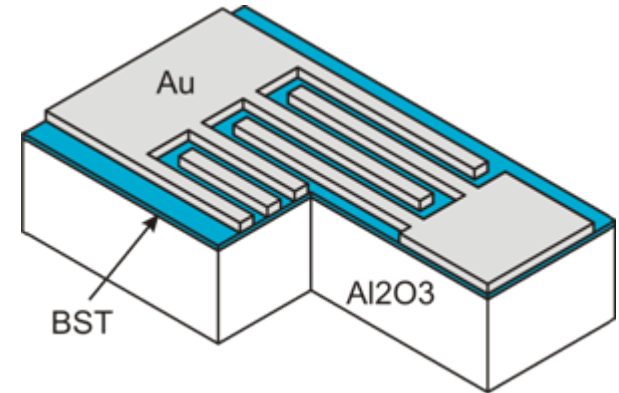
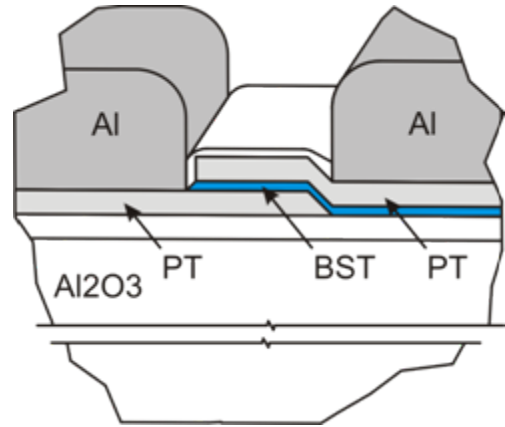
- Antenna
- Power amplifier

Antenna Mismatch



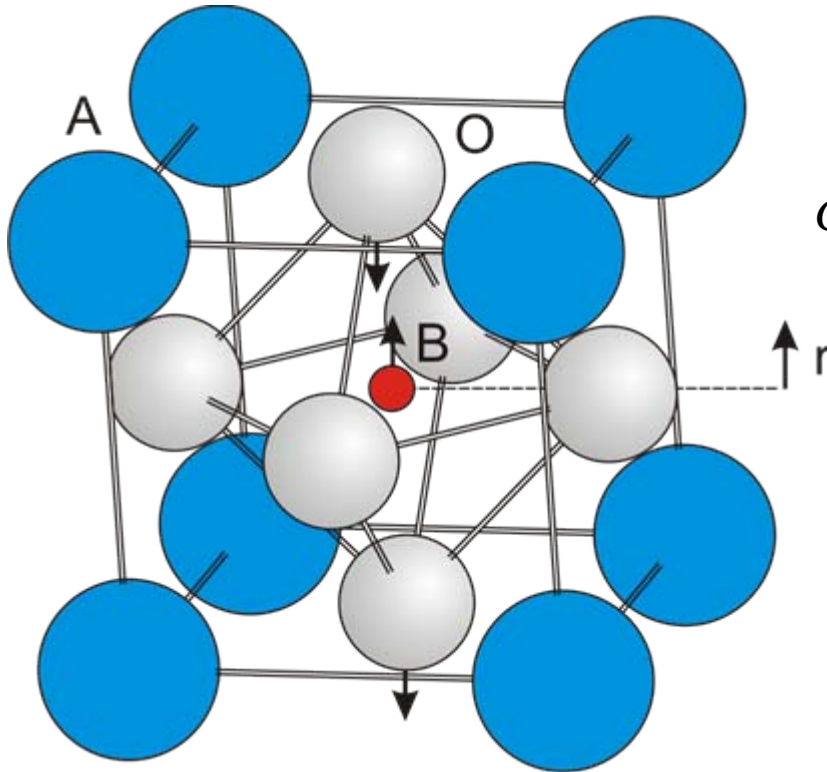
- Detuning of antenna impedance
- Near-field distortion

Ferroelectric Varactors



- Thin-film
 - Low bias voltage
 - High C value
 - High tunability
 - Resonances
- Thick-film
 - High bias voltage
 - Low C value
 - Low tunability
 - Large area

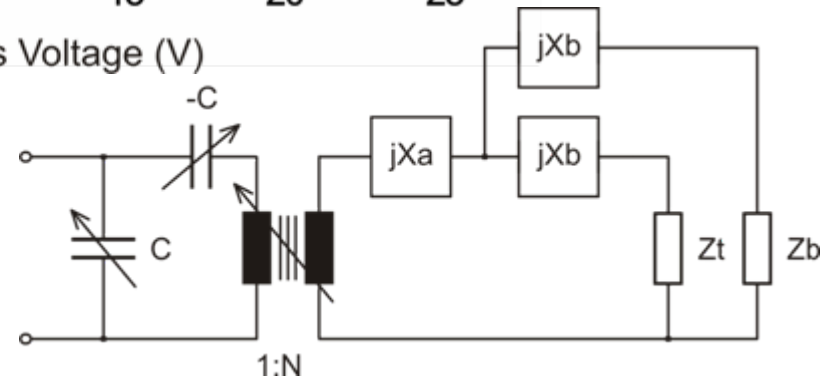
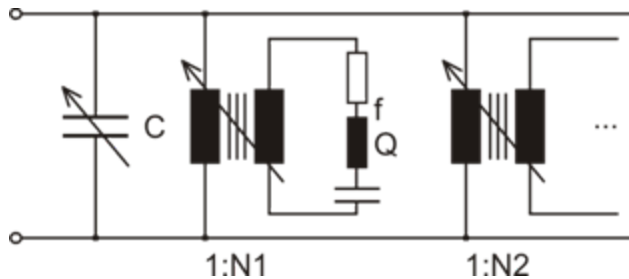
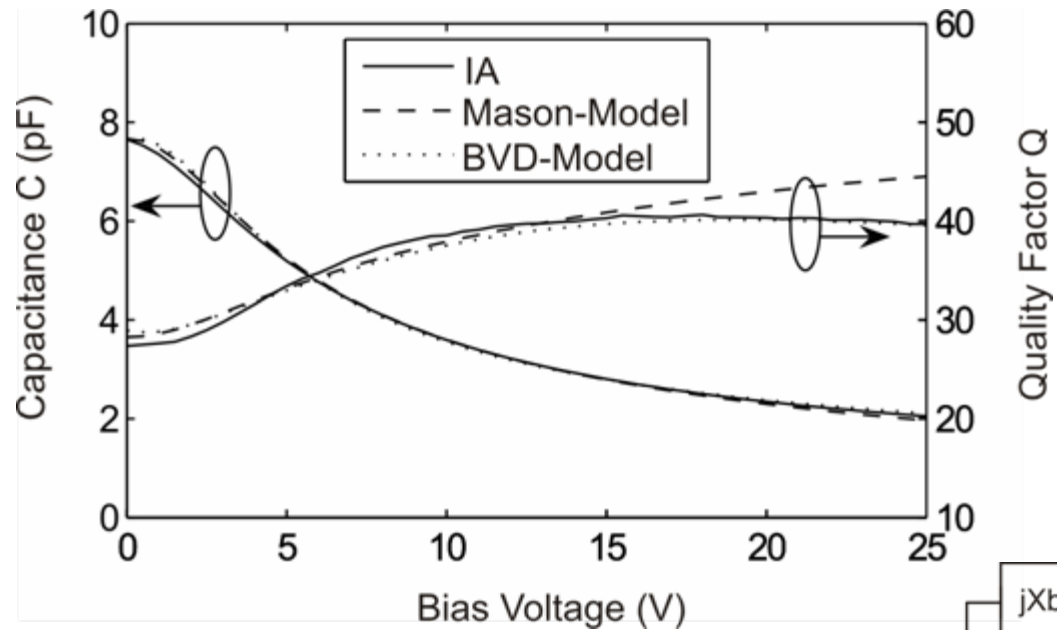
Ba_xSr_(1-x)TiO₃ – Crystal



$$C_{BST}(U) = \frac{C_{\max}}{2 \cosh\left(\frac{2}{3} \sinh^{-1}\left(\frac{2U}{U_{C_{\max}/2}}\right)\right) - 1}$$

- Perovskite-type crystal
- Ba / Sr ratio

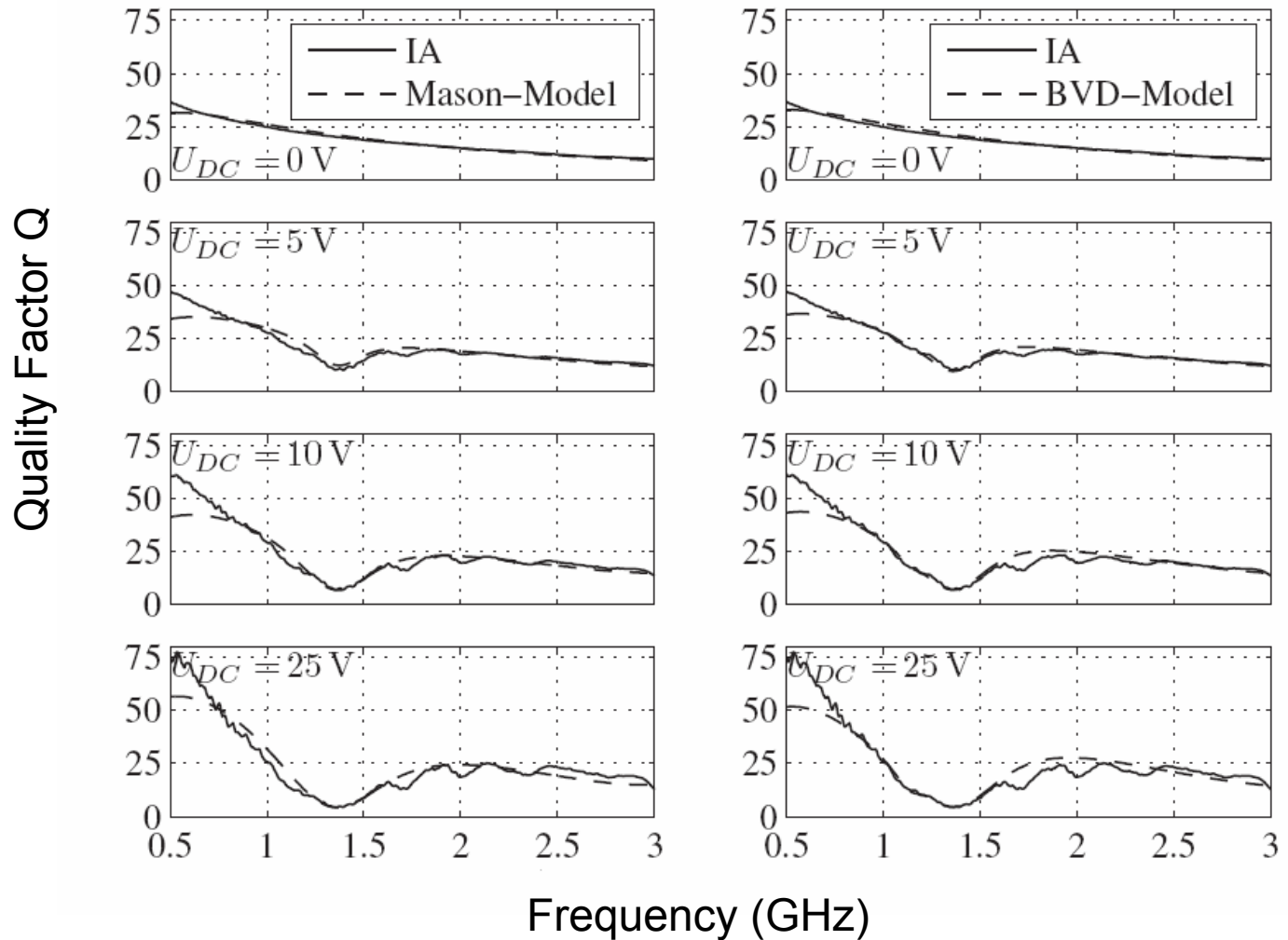
Varactor Modelling



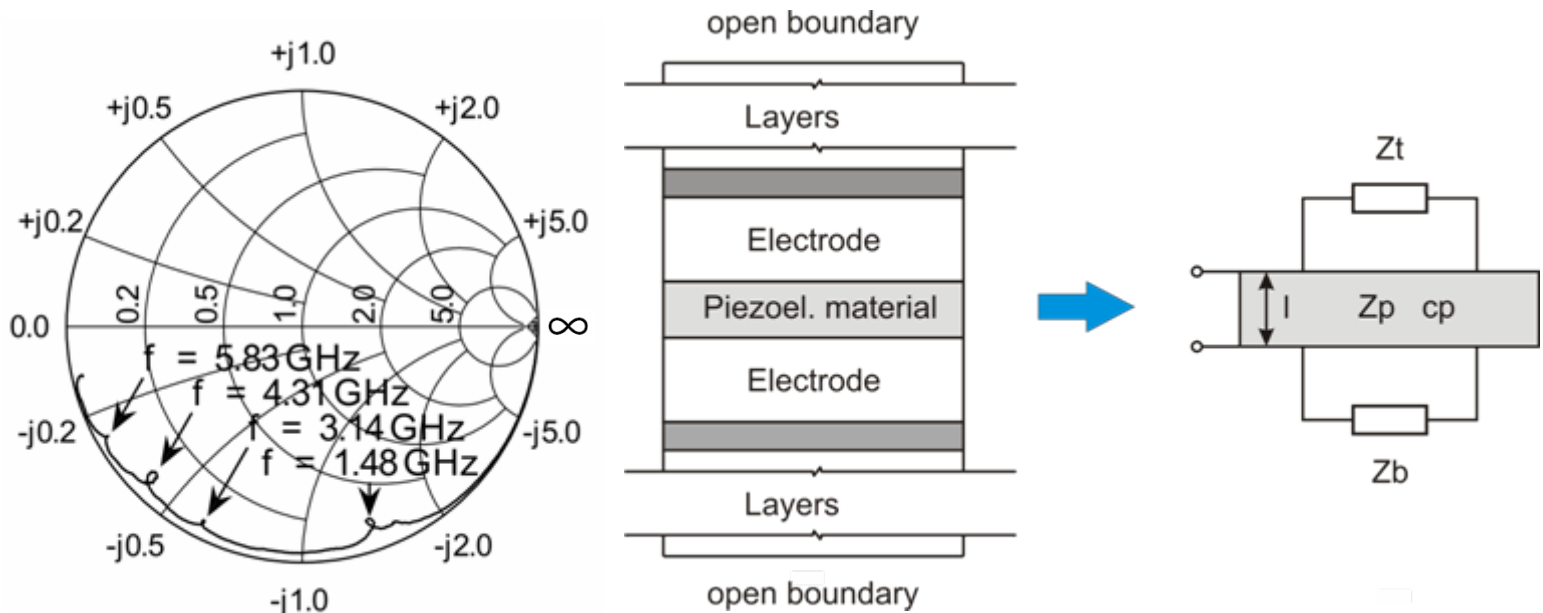
- BVD model

- Mason model

Varactor Modelling (2)

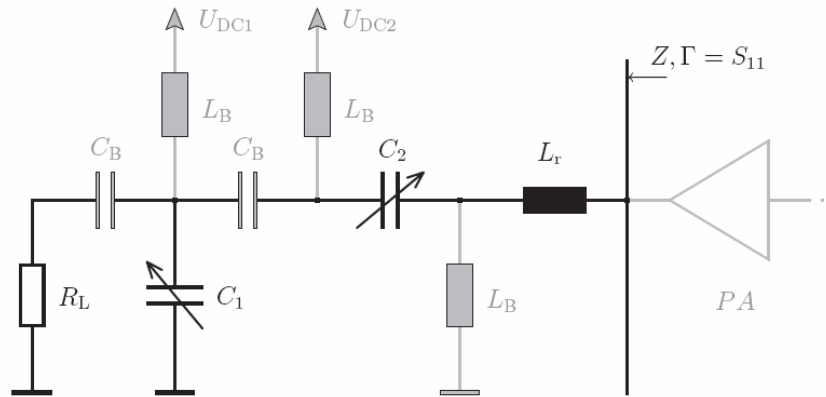


Acoustic Resonances



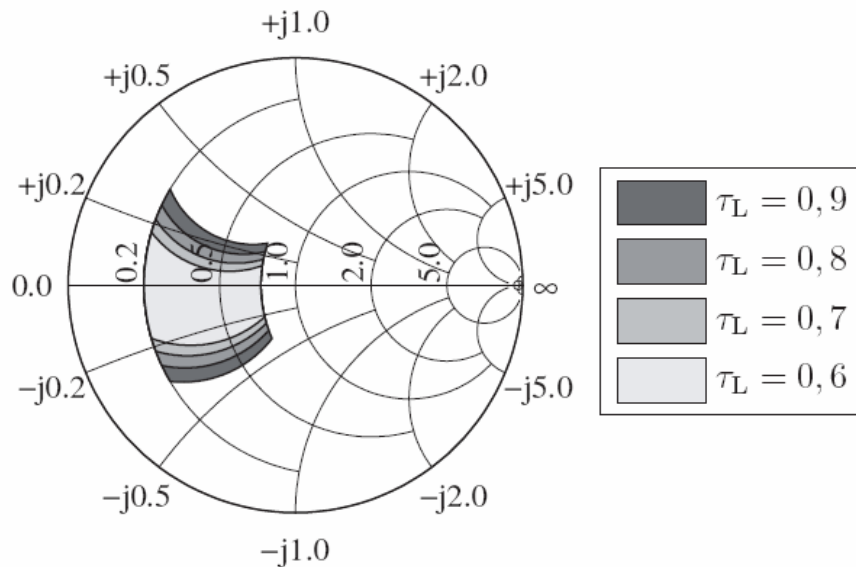
- Layered material stack
- Discrete acoustic impedances
- Parasitic “FBAR”

L - Matching Network



- PA Matching

- Tunable L is series LC

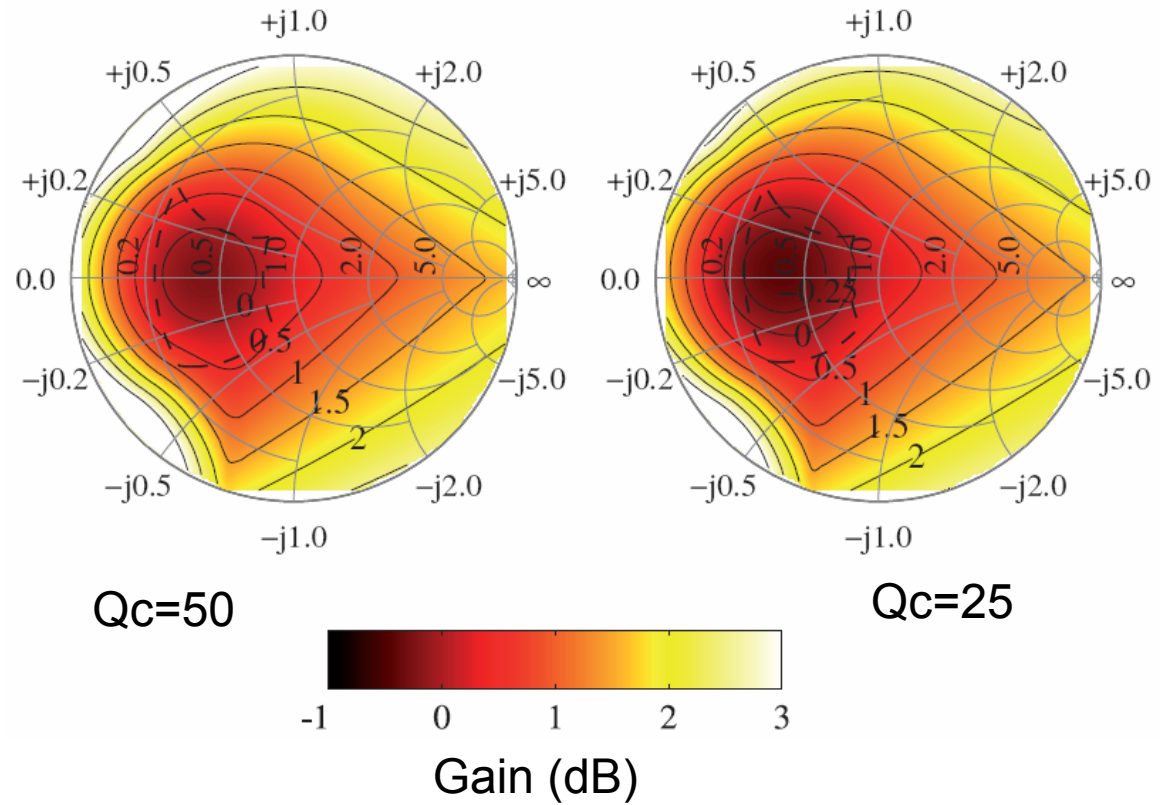


- Small matching area

L - Network Gain

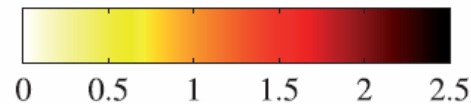
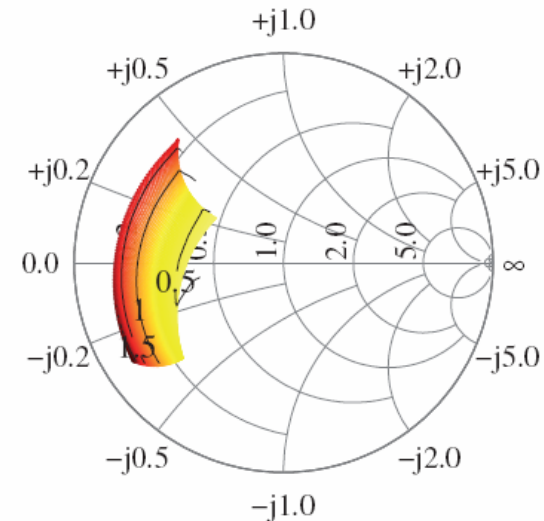
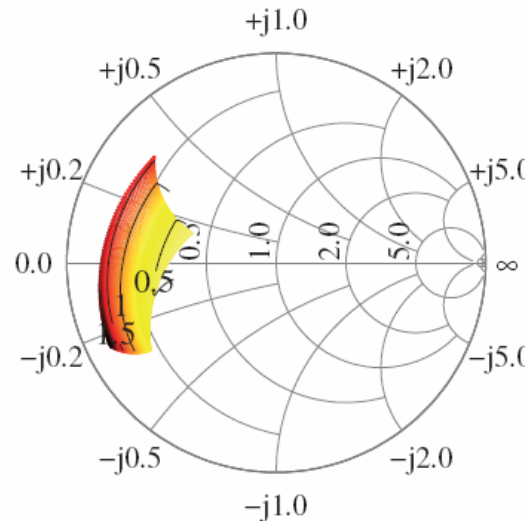
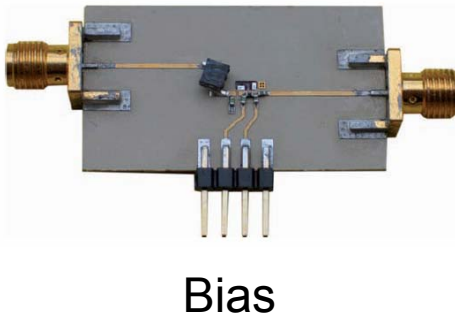
Fixed MN with
 $Z_{in}=25\Omega$

SMD 0402
components



- Losses for minor impedance variations

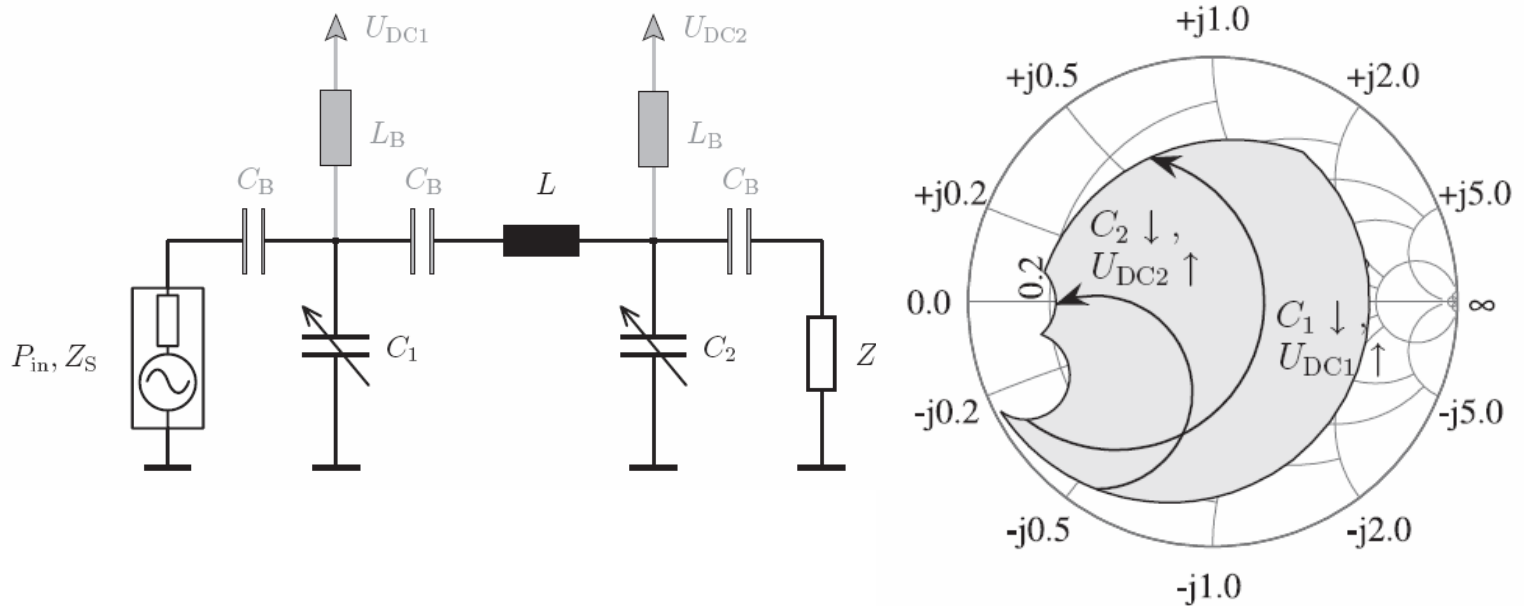
L - Matching Area



Transducer Power Loss (dB)

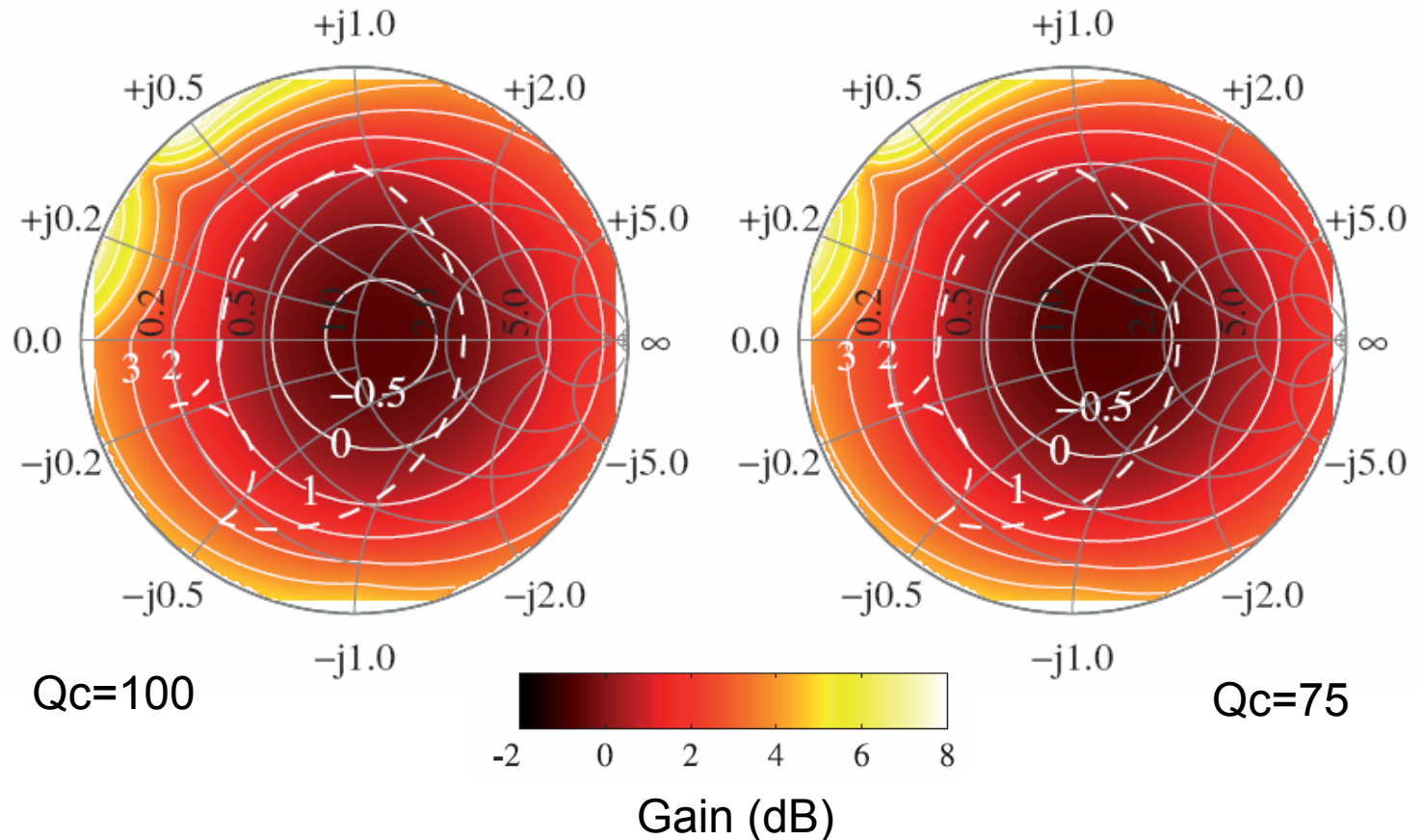
- Excellent agreement
- Dynamically adjustable PA impedance

Π - Matching Network



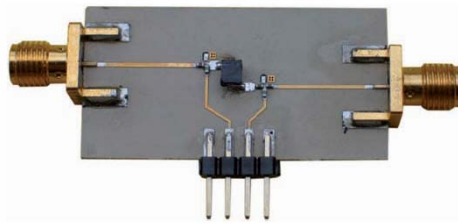
- High C value
- Suitable for low impedances
- Low IMD

Π – Network Gain

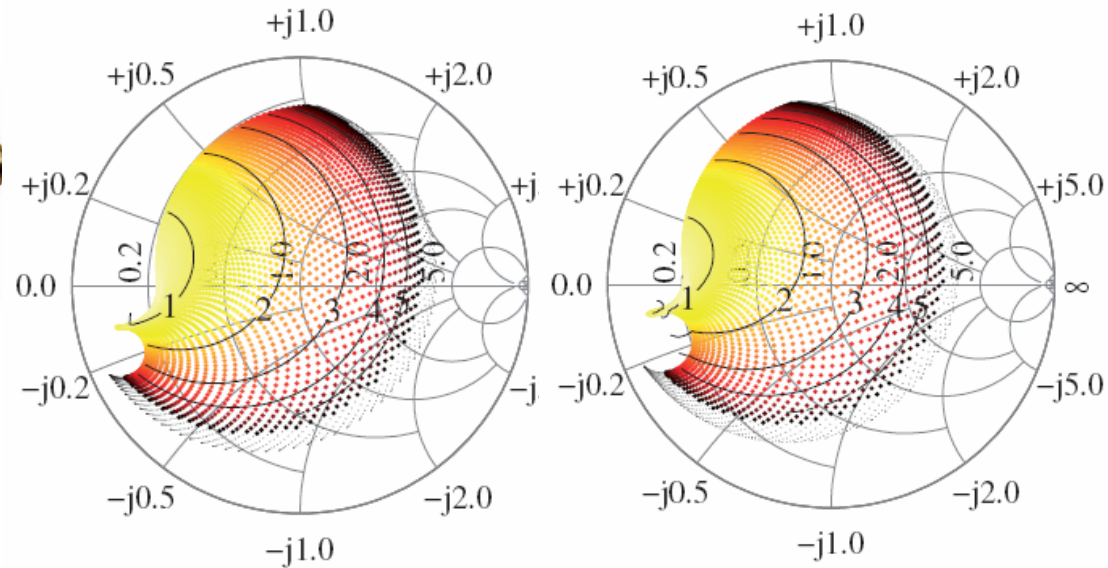


- Gain for significant impedance variations

Π – Matching Area



Bias



Simulated

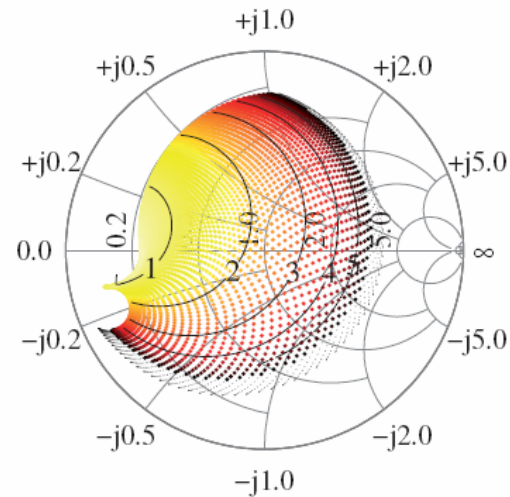


Measured

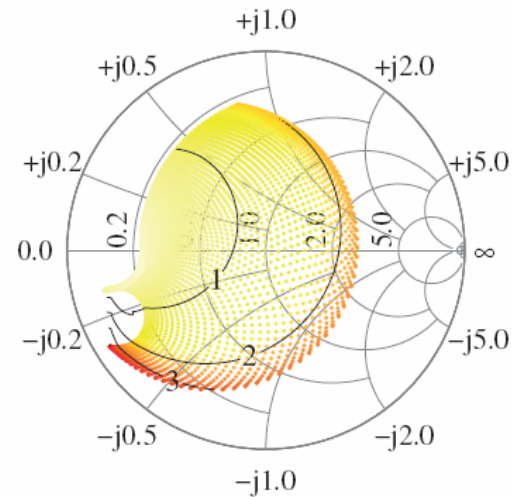
Transducer Power Loss (dB)

- Excellent agreement
- Losses increase for higher impedances

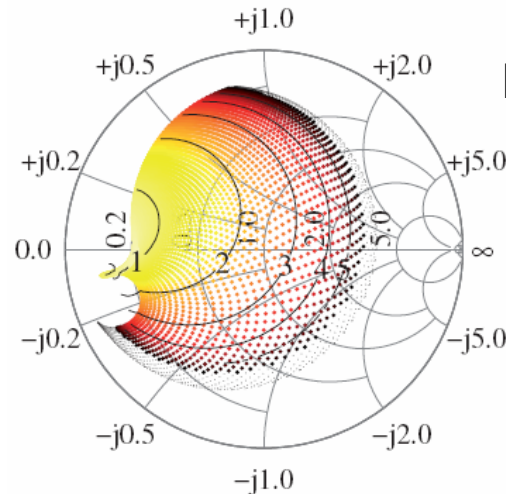
Assembly Parasitics



Simulated with bond wires



Simulated without bond wires

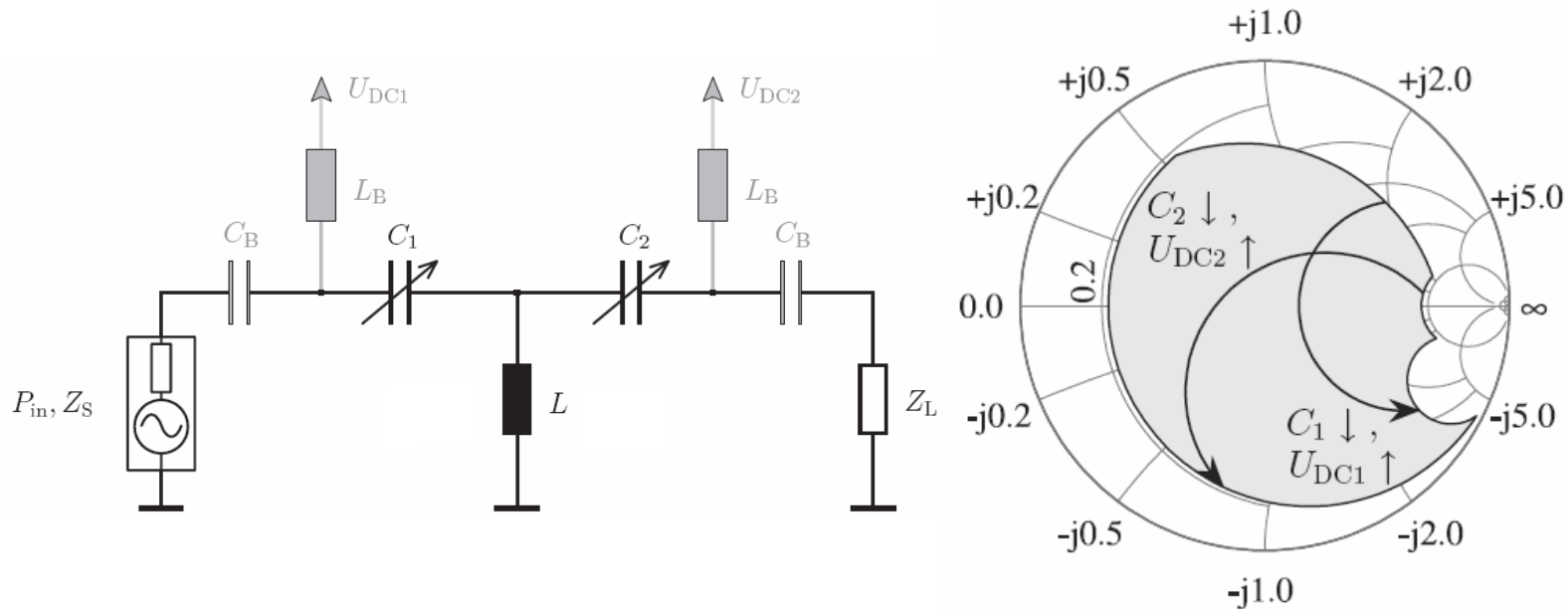


Measured



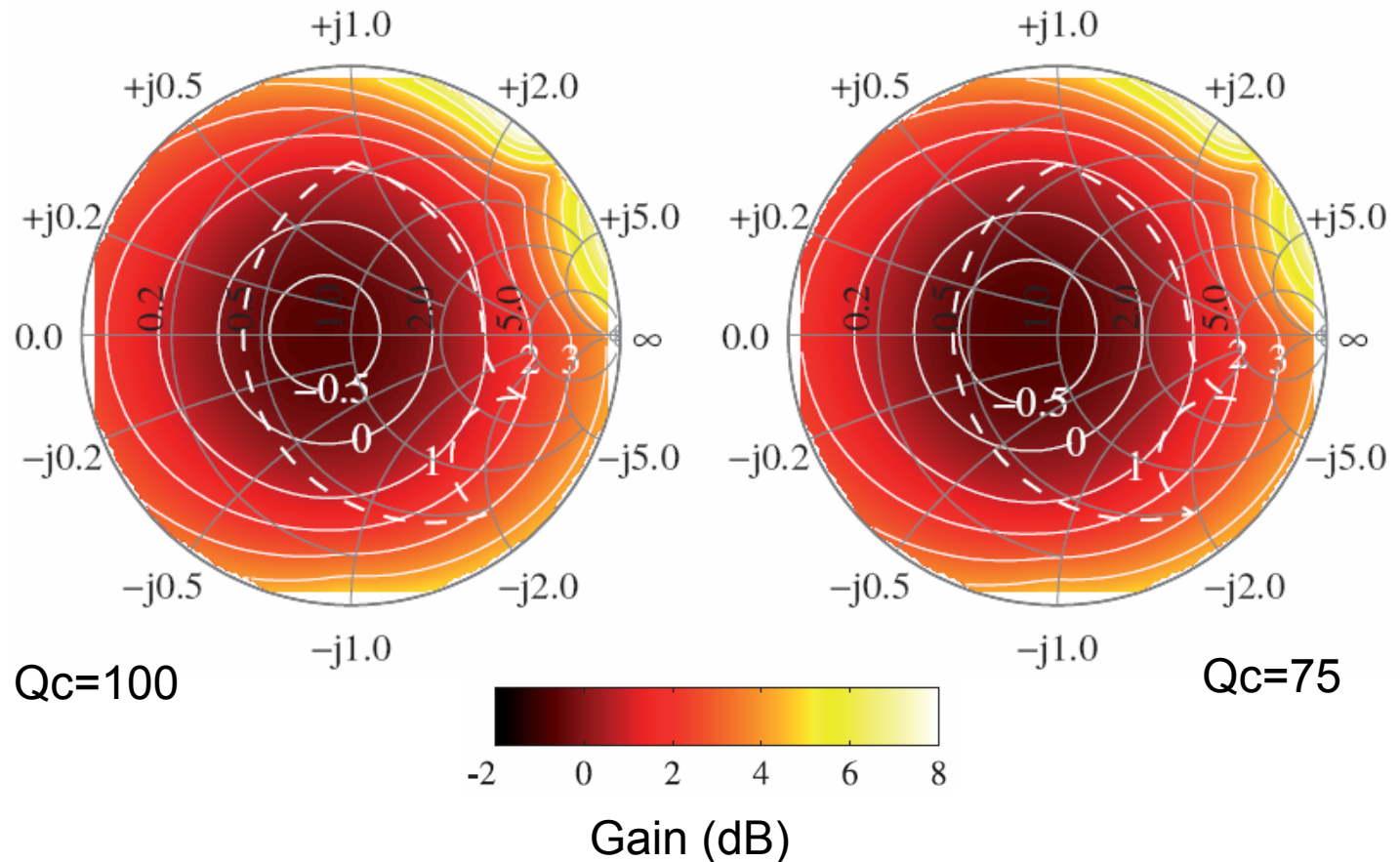
Transducer Power Loss (dB)

T – Matching Network



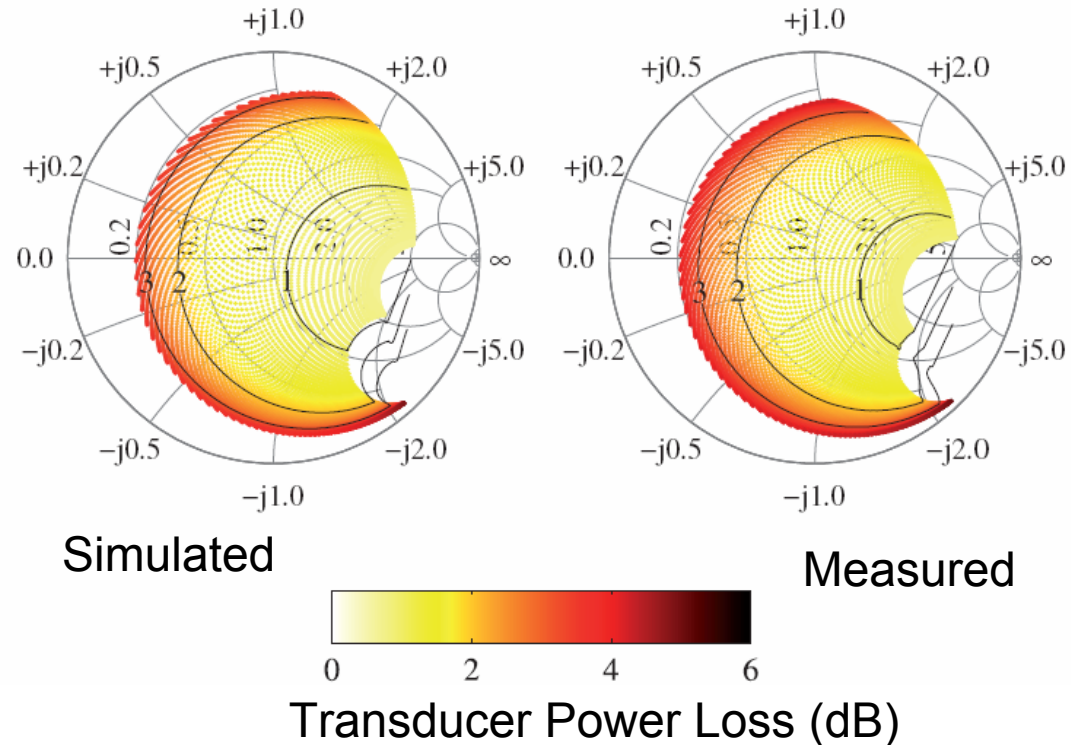
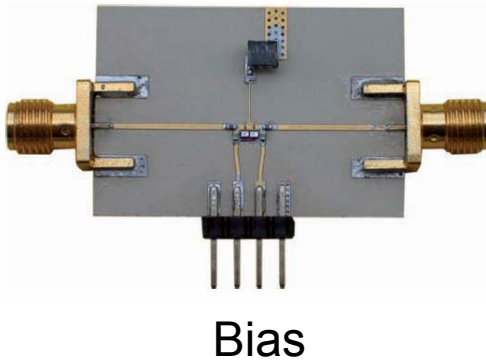
- Low C values
- Suitable for high impedances
- High IMD

T – Network Gain



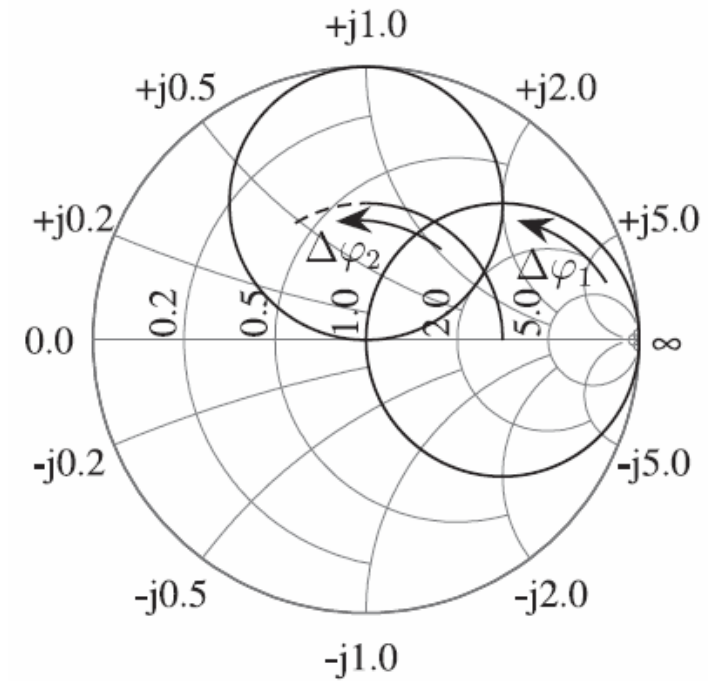
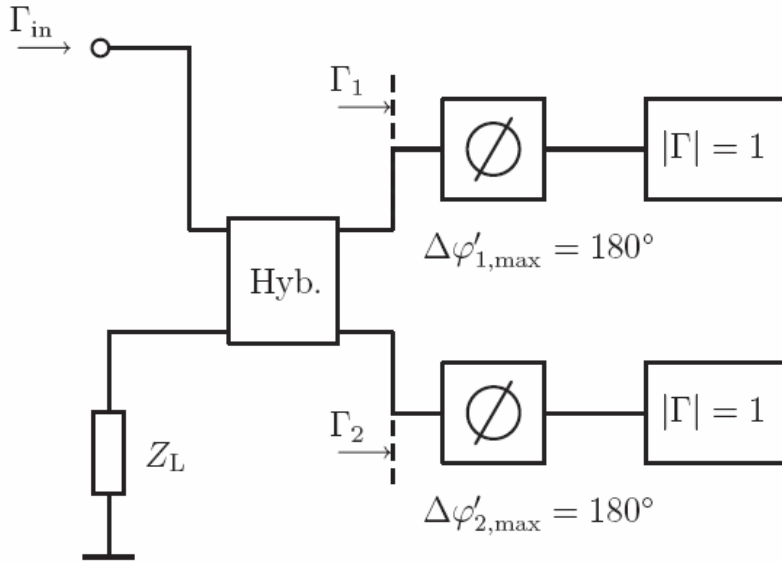
- Gain for significant impedance variation

T – Matching Area



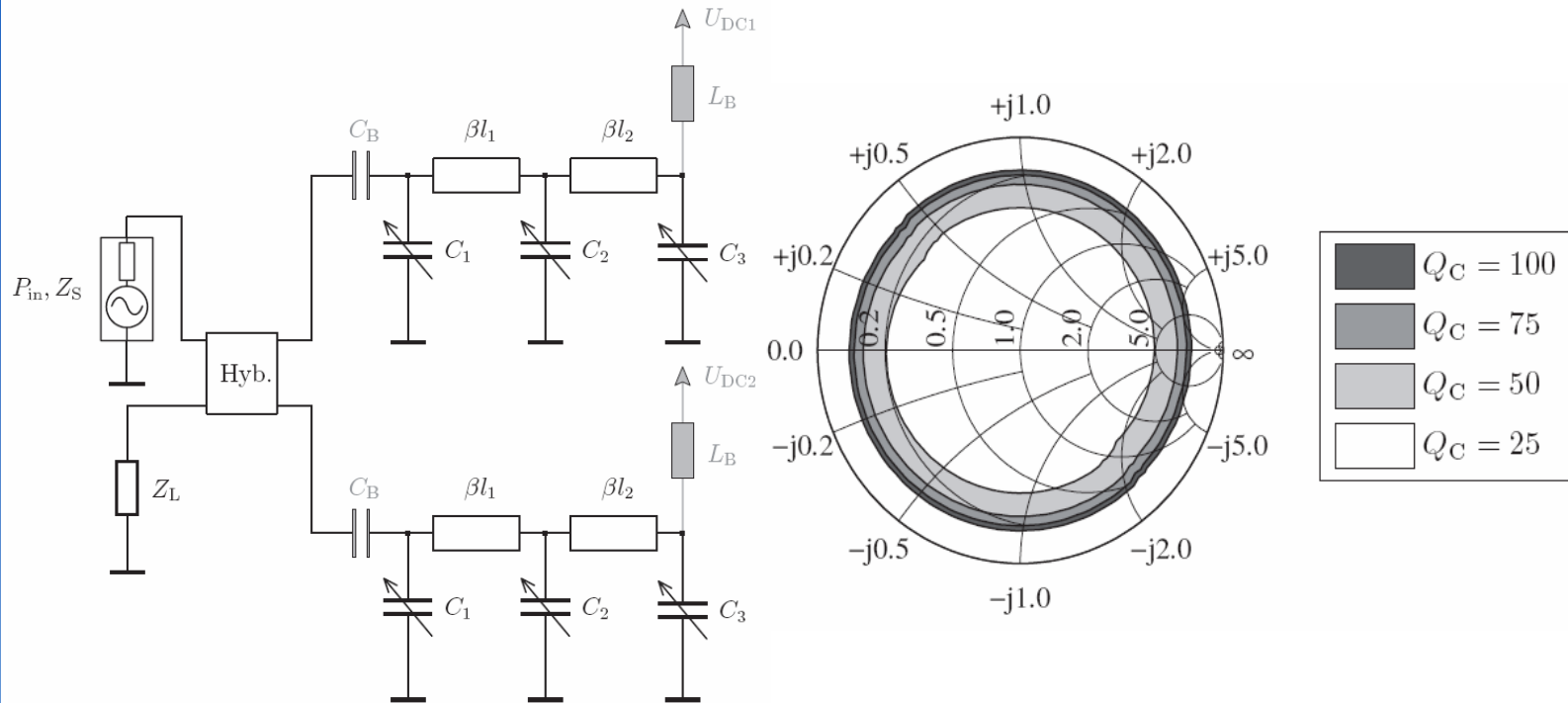
- Excellent agreement
- Higher losses for low impedances

Reflection – Matching Network



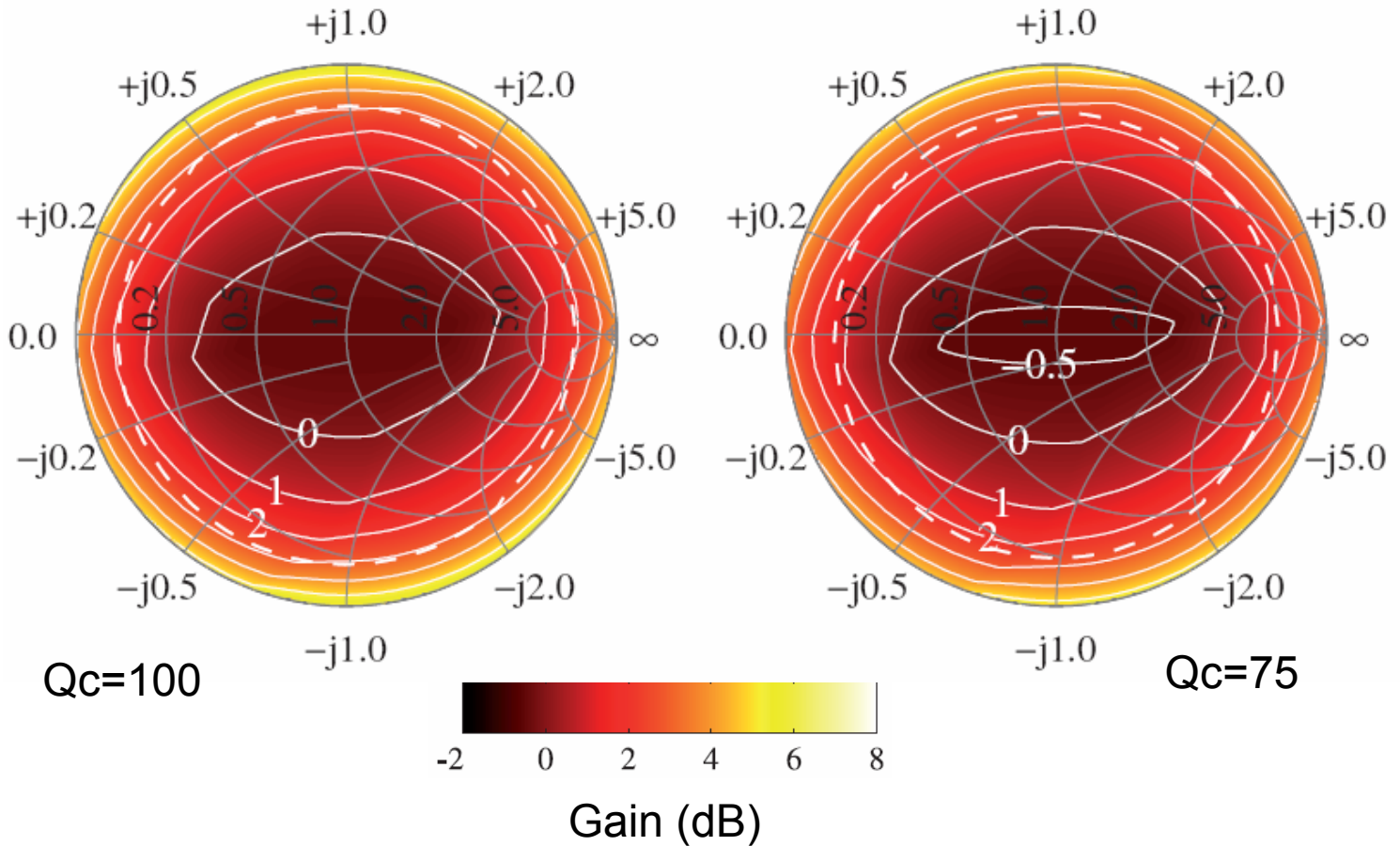
- Total Smith-chart area coverage
- Hybrid coupler and phase shifters
- Large circuit dimension

Reflection Type Circuit



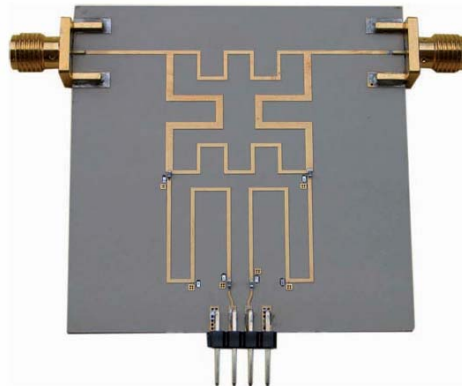
- High Q values for varactors lead to large matching area

Reflection – Network Gain

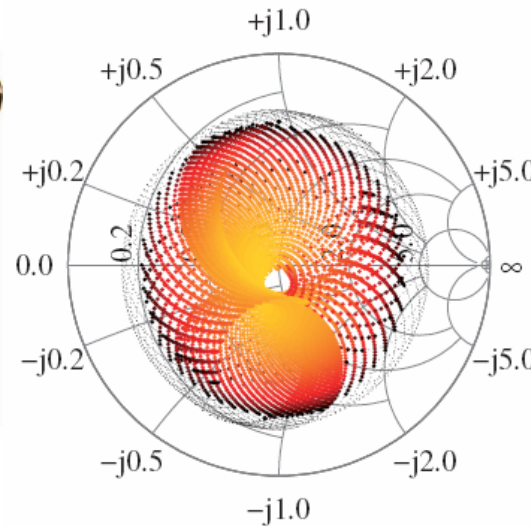


- Gain for significant impedance variation

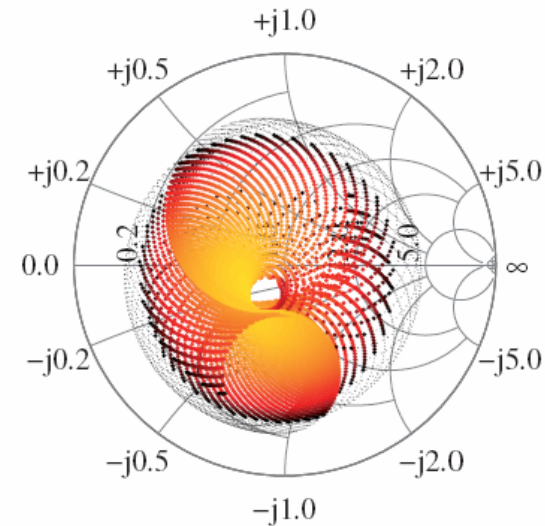
Reflection – Matching Area



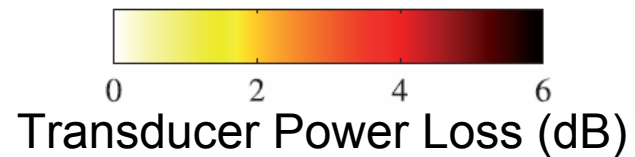
Bias



Simulated

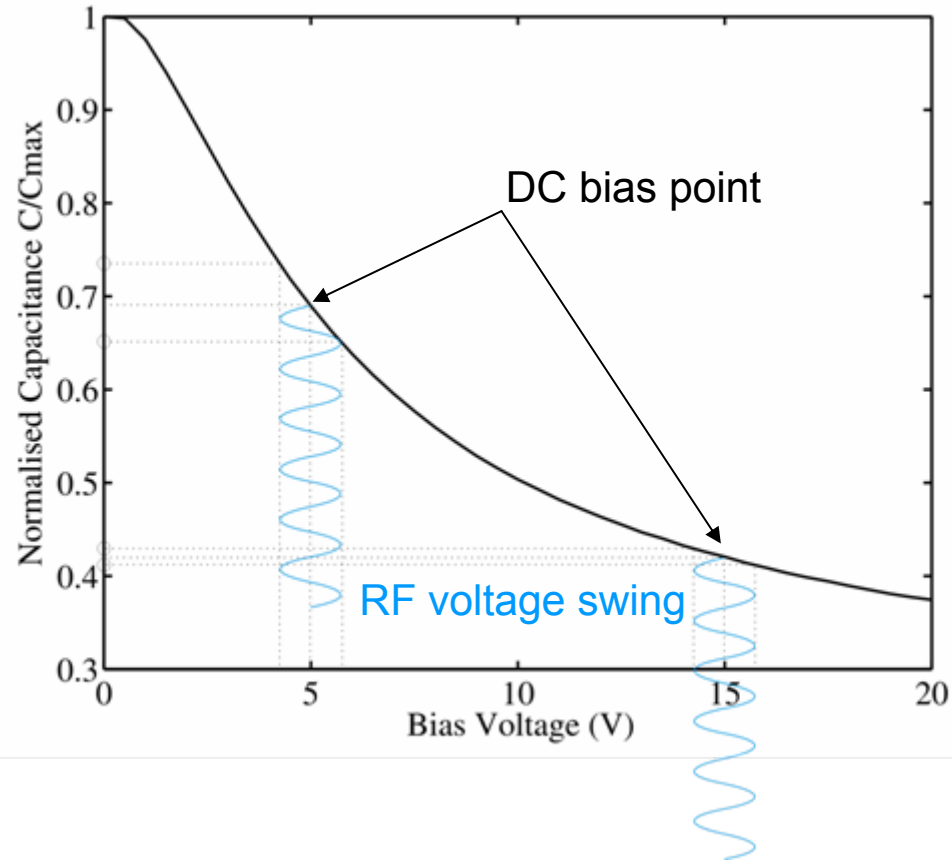


Measured



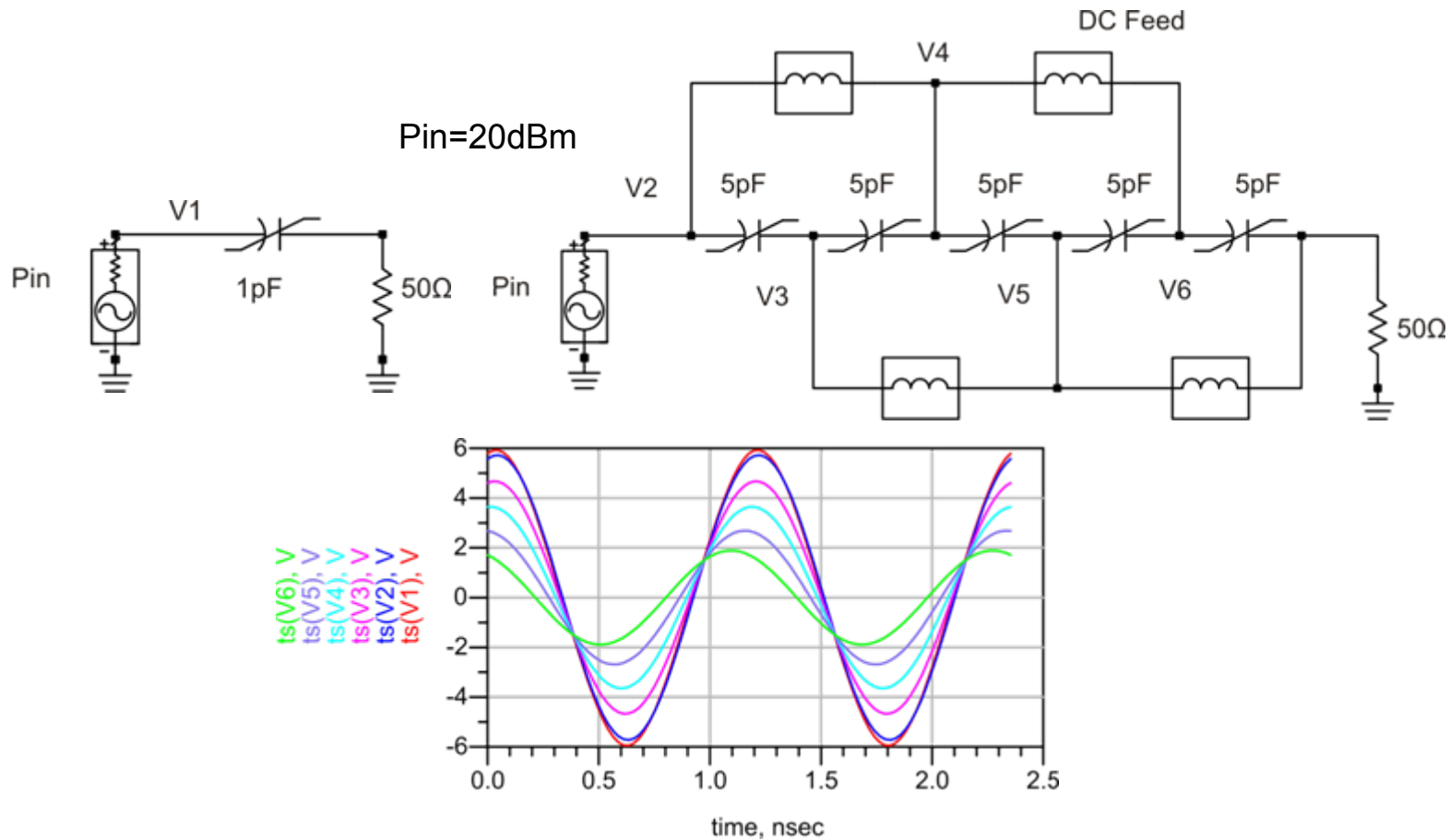
- Excellent agreement
- Symmetric matching area

Varactor Nonlinearity



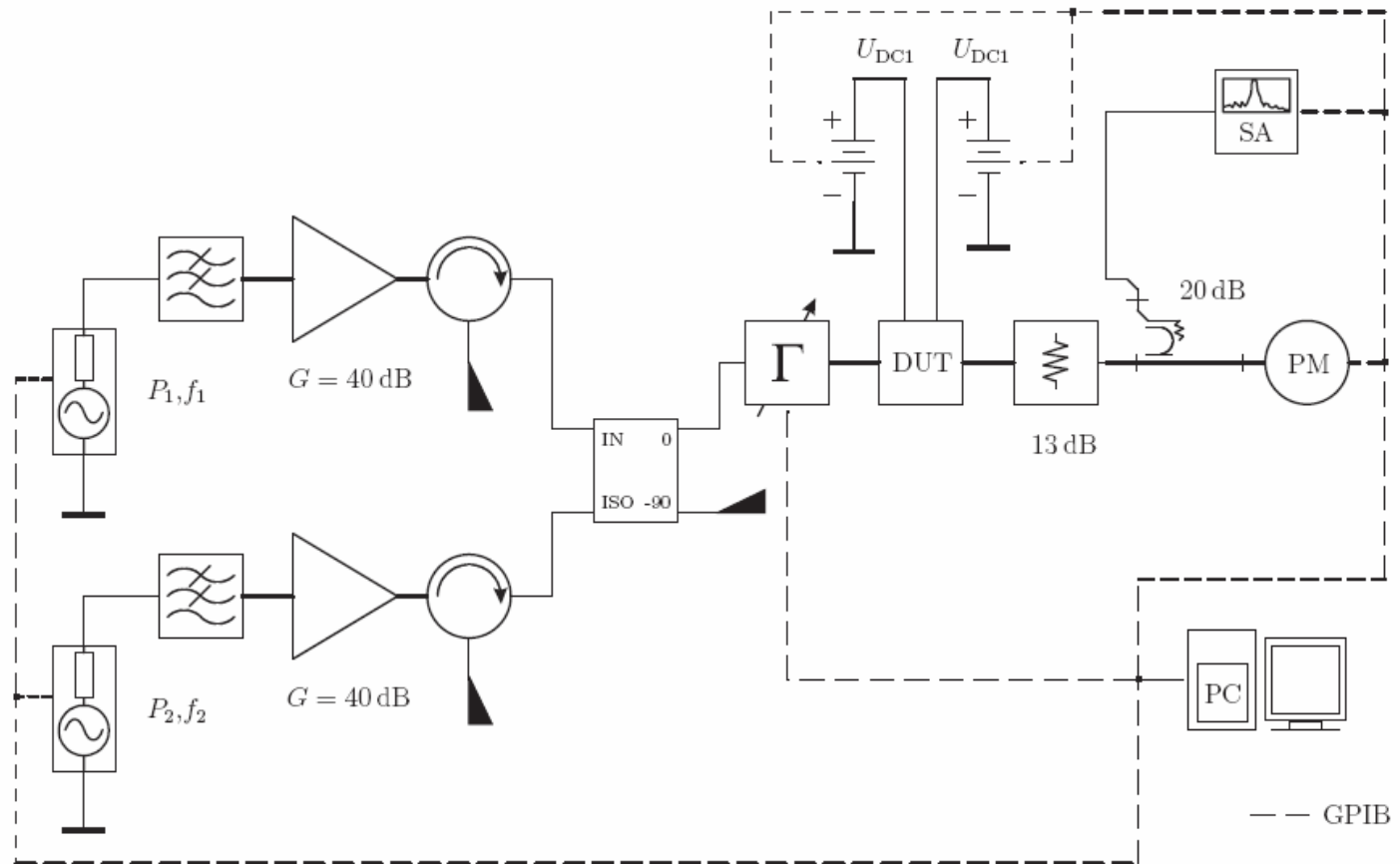
- High tunability results in high IMD

Cascaded Capacitors



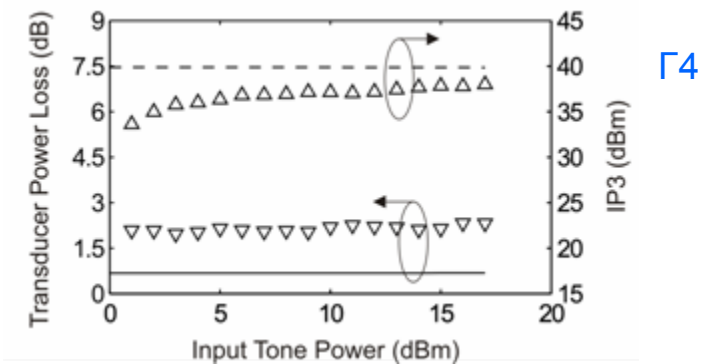
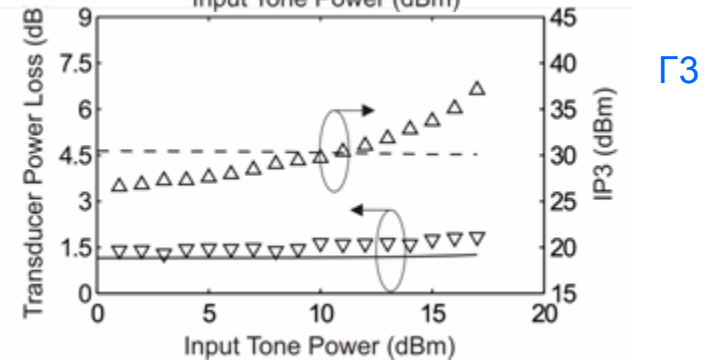
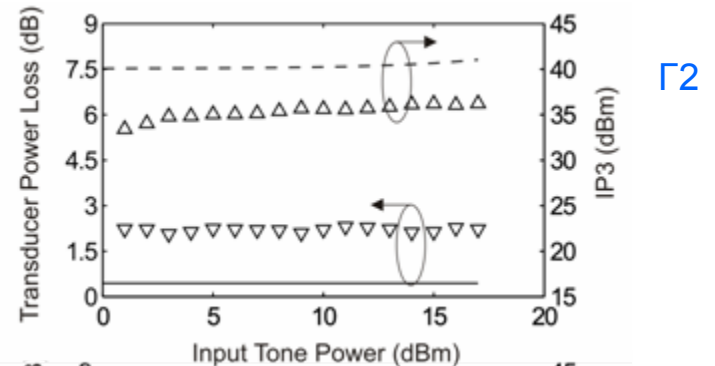
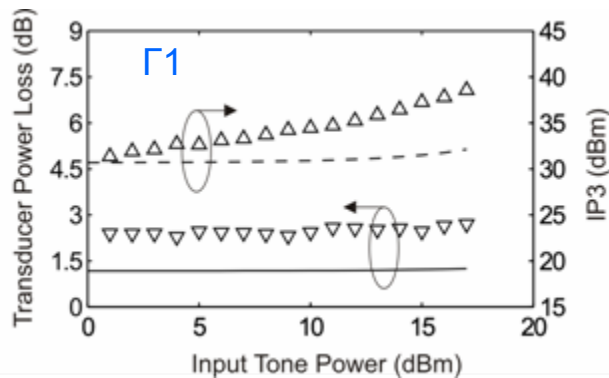
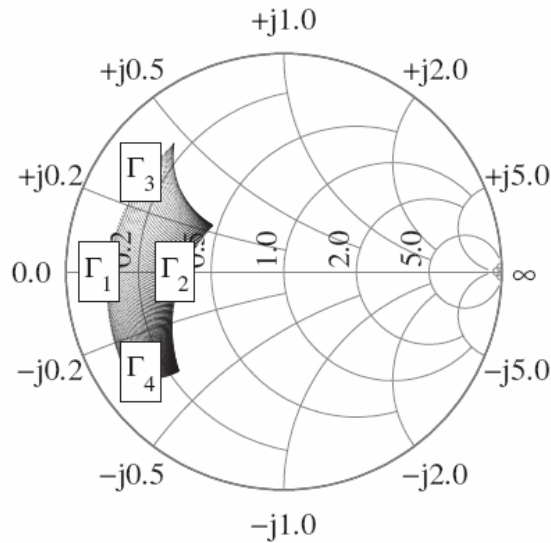
- Smaller voltage swing for cascaded C

Two-Tone Setup

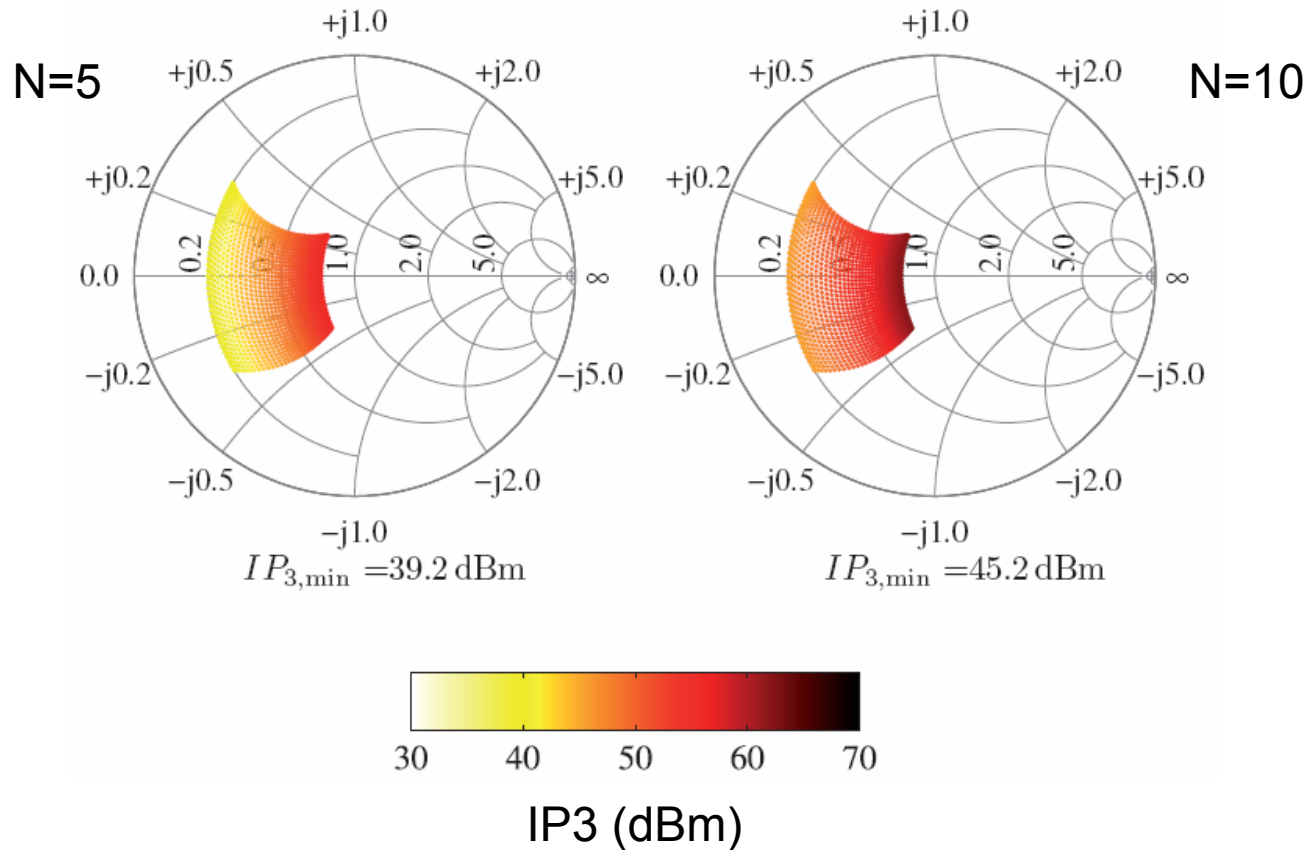


- Typical 2-tone setup

L – Linearity

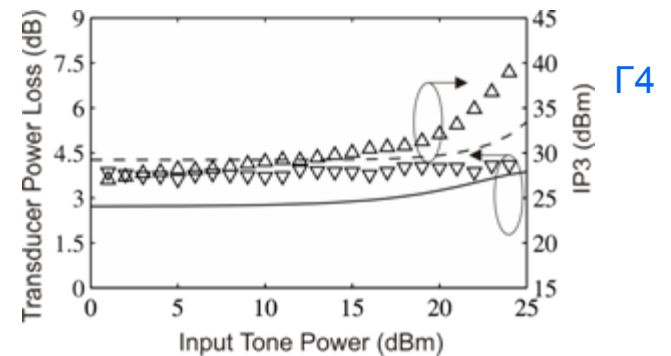
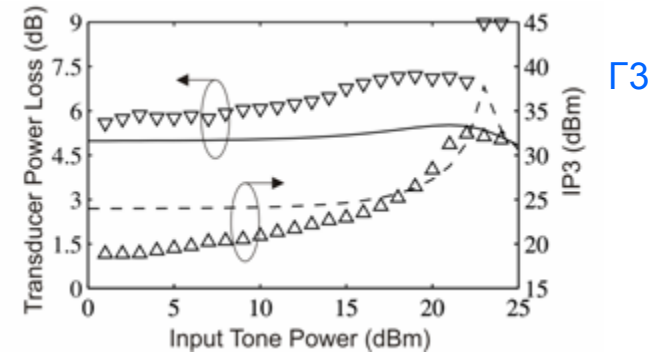
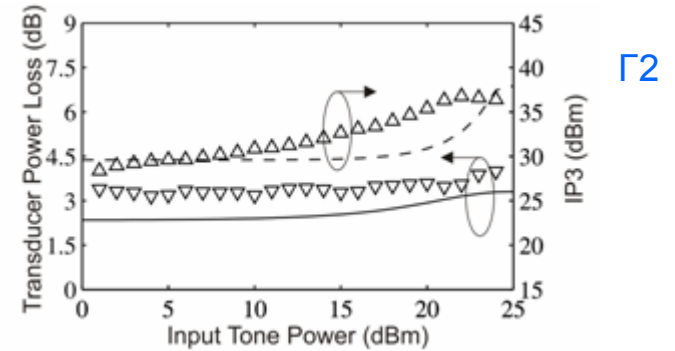
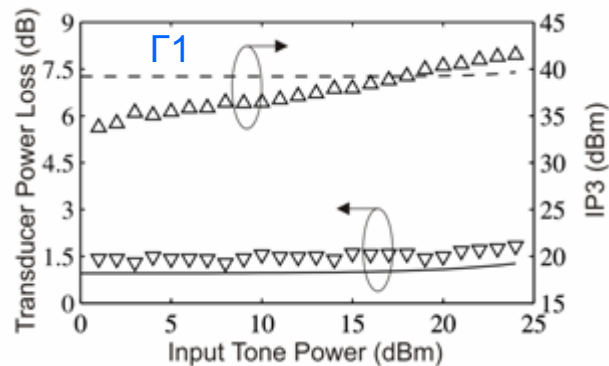
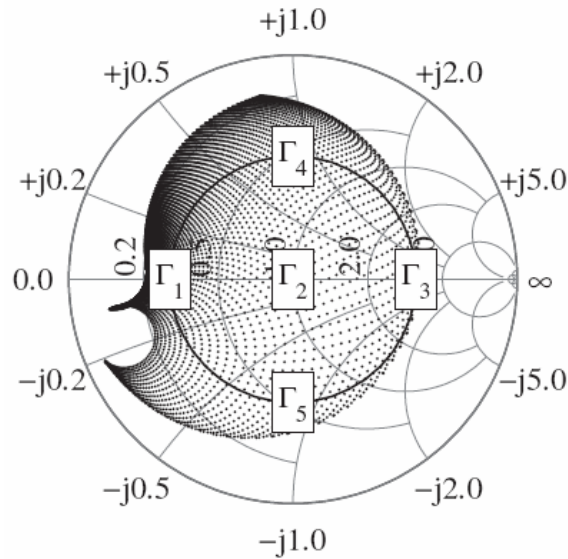


L – Network IP3

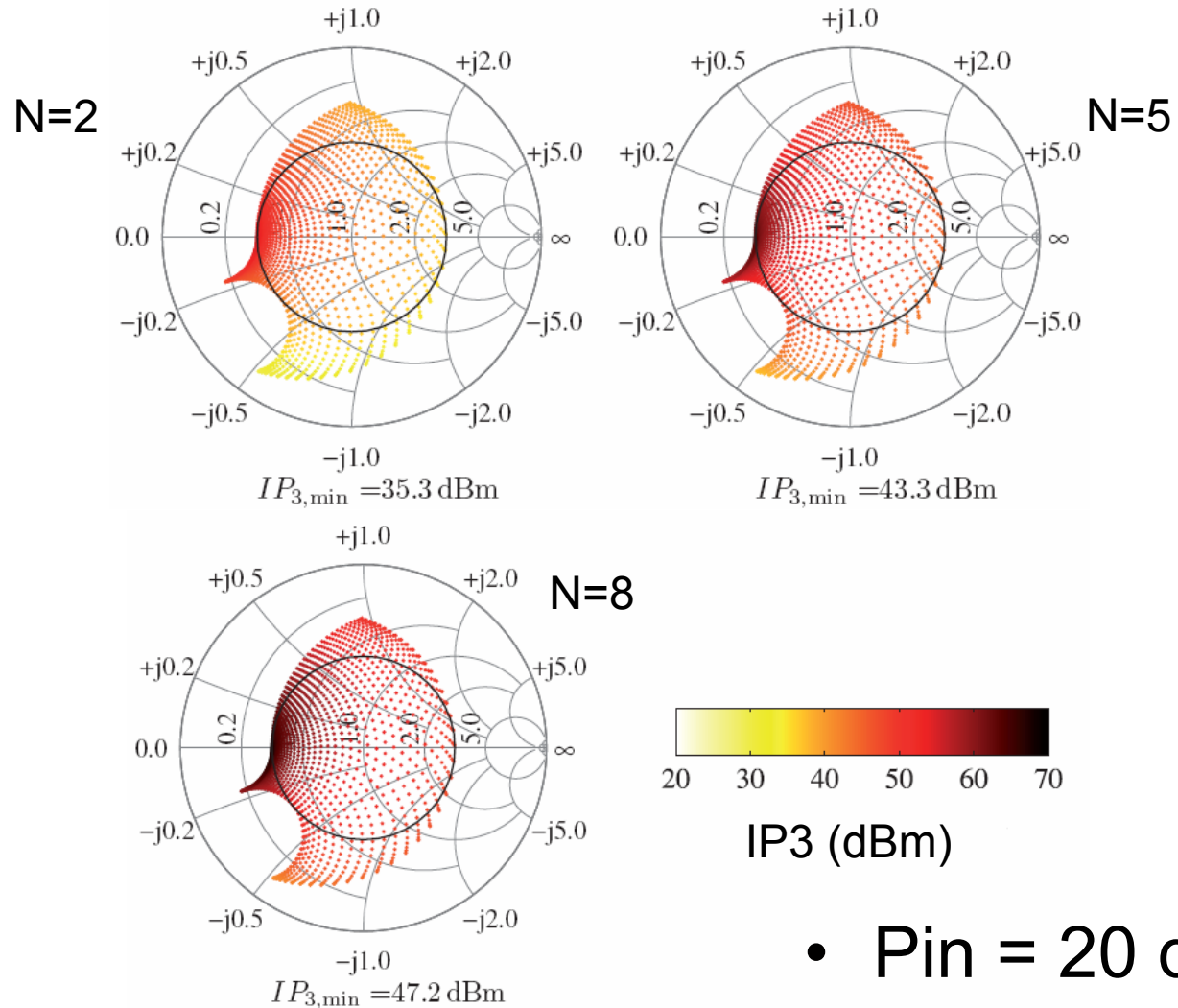


- $P_{in} = 20$ dBm

Π – Linearity

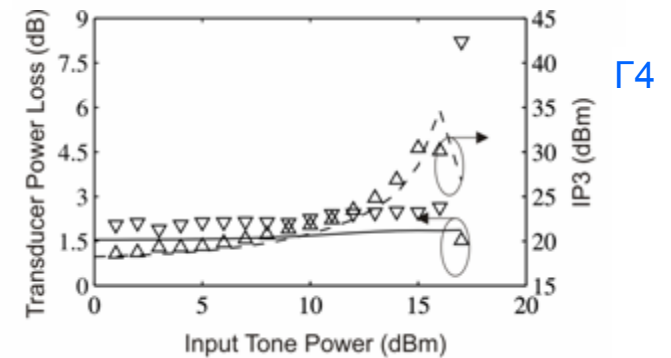
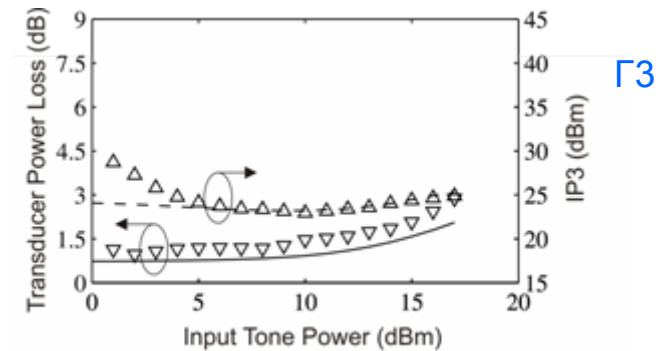
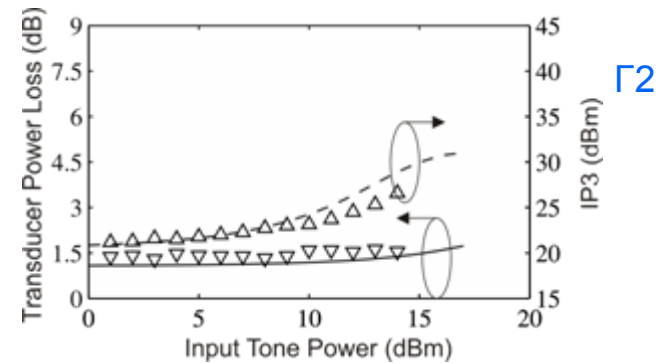
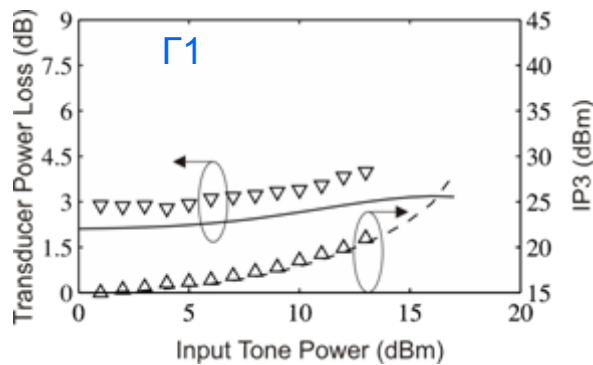
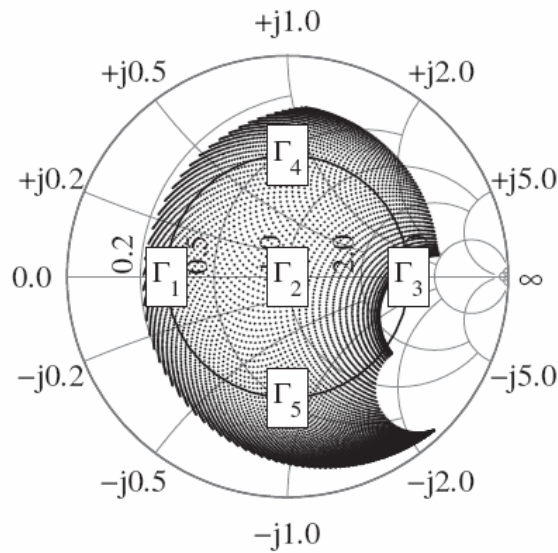


Π – Network IP3

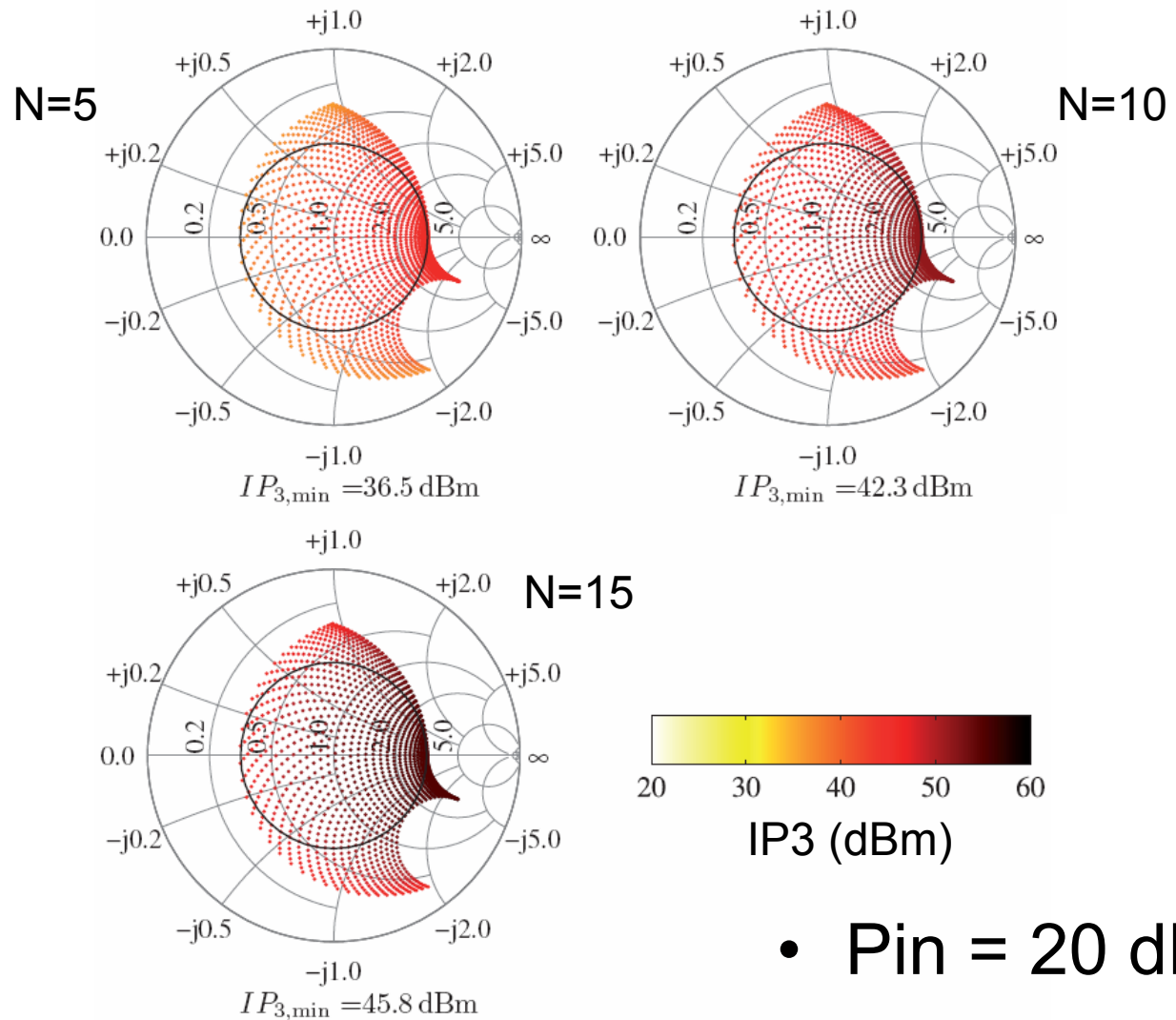


- $P_{in} = 20$ dBm

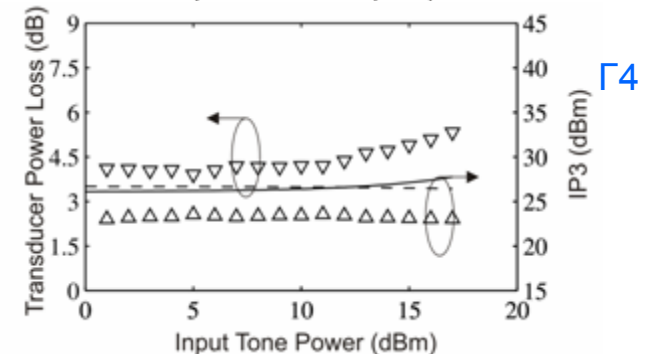
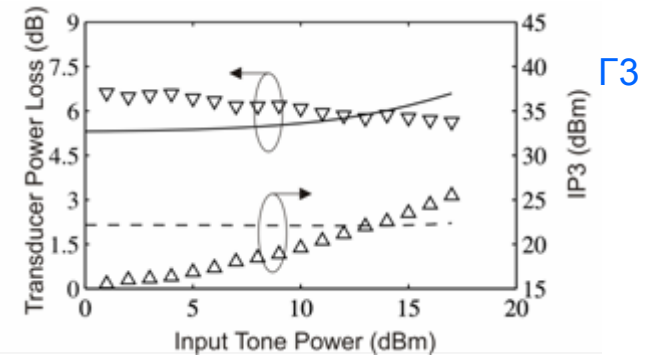
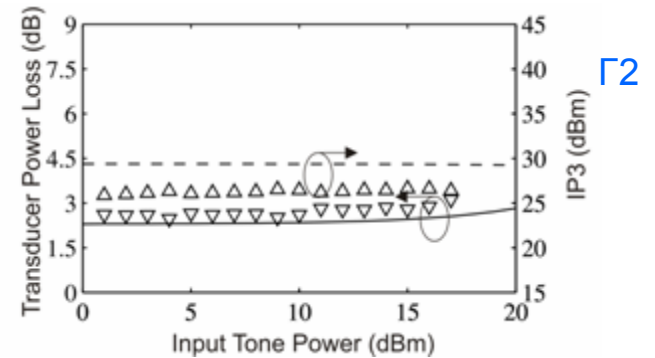
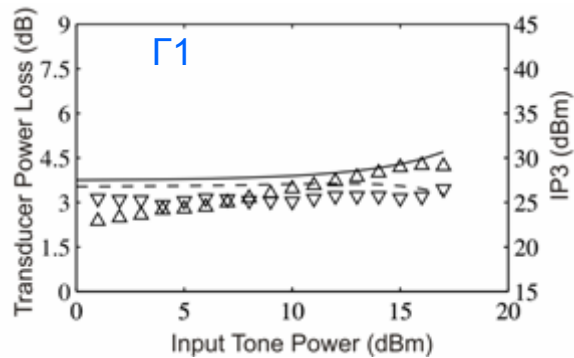
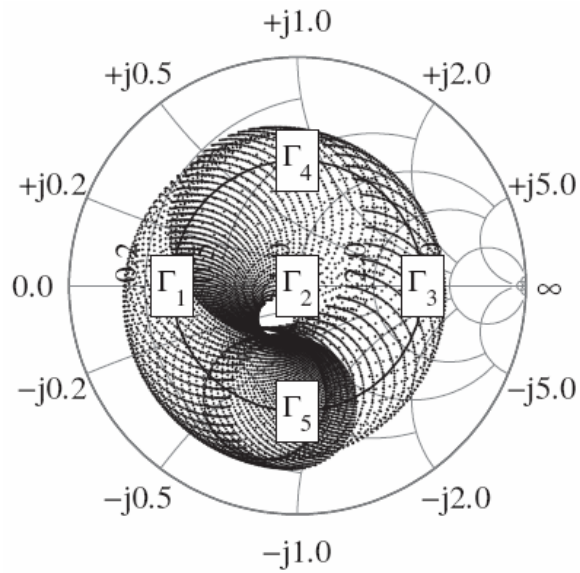
T – Linearity



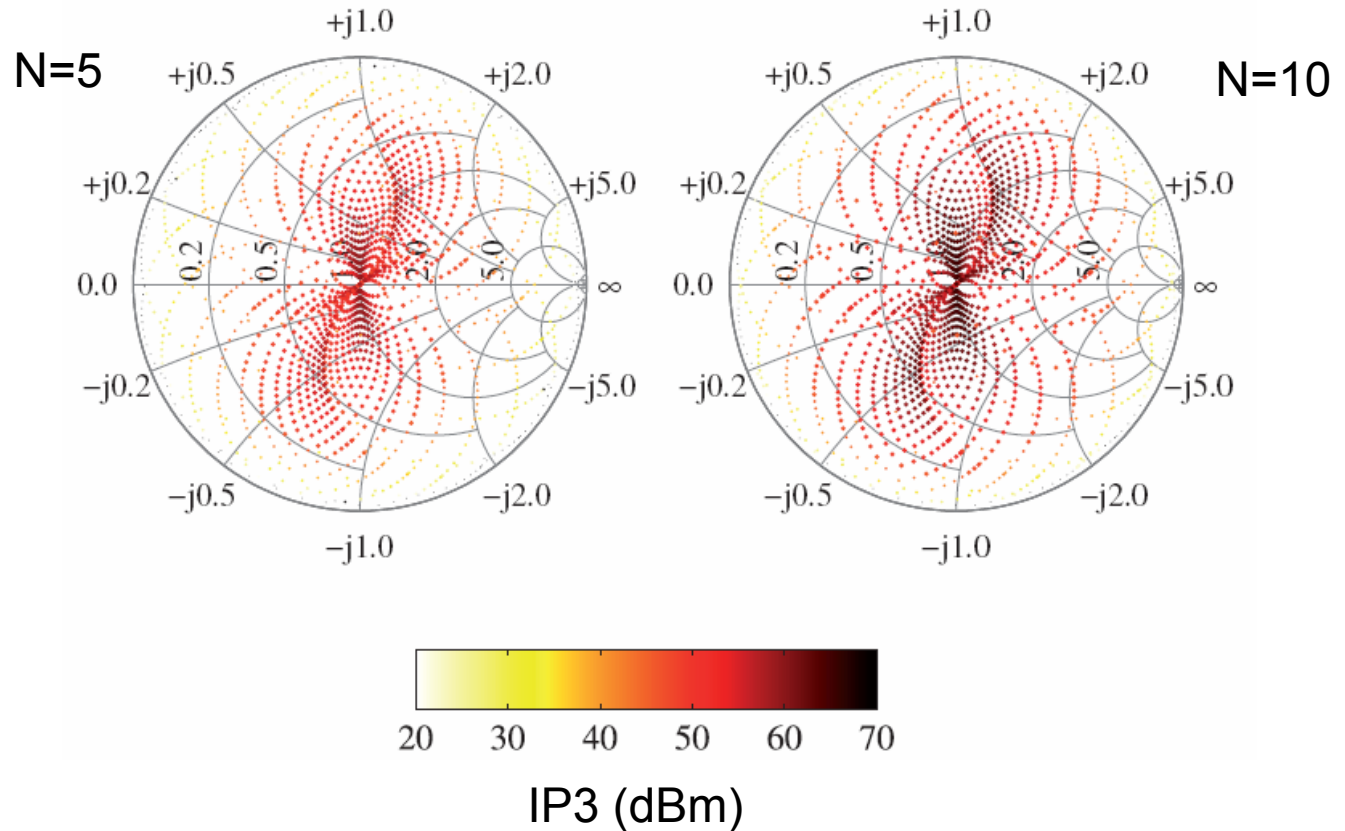
T – Network IP3



Reflection MN – Linearity



Reflection MN – Network IP3



- $P_{in}=20\text{dBm}$

Summary

- BST thin-film varactors & modelling
- Matching networks
 - L-topology
 - Π -topology
 - T-topology
 - Reflection-type
- Linear and nonlinear investigation
- Measurements

Thank you for your attention

E. Lourandakis

06 / 16 / 2008

37

IMS 2008 - Workshop

